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| Notice of References Cited | Application/Control No. 10/500,074 | Applicant(s)/Patent Under Reexamination SAKAKI ET AL. | |
| | Examiner John P. Sheehan | Art Unit 1742 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-6,623,541 B2 | 09-2003 | Sakaki et al. | 75/232 |
| * | B | US-2003/0041920 A1 | 03-2003 | Hoshi et al. | 148/122 |
| * | C | US-6,399,150 B1 | 06-2002 | Yoshimura et al. | 427/242 |
| * | D | US-2002/0036029 A1 | 03-2002 | Kikugawa et al. | 148/101 |
| * | E | US-6,326,087 B1 | 12-2001 | Nishiuchi et al. | 428/611 |
| * | F | US-US 20010030590A! | 10-2001 | Nishiuchi et al. | 335/302 |
| * | G | US-5,876,518 A | 03-1999 | Hasegawa et al. | 148/302 |
| * | H | US-4,966,668 | 10-1990 | Veistinen, Mauri K. | 427/528 |
| * | I | US-4,837,114 | 06-1989 | Hamada et al. | 427/527 |
| * | J | US-4,770,723 | 09-1988 | Sagawa et al. | 148/302 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------|
| * | N | JP 56-81908 | 07-1981 | Japan | Okonogi et al. | --- |
| | O | 2000-40610 | 08-2000 | Japan | Okabe | --- |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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